

Overview

KEMET's ALP22 and ALT22/23 Series of capacitors features low ESR, high ripple current ratings and outstandingly good high frequency impedance. KEMET's ALP/T22/23 series of capacitors has a very high CV per unit volume.

It should be pointed out that the ALP solder pin and ALT solder tag range details are incorporated herein, primarily, for maintenance/replacement purposes.

- Solder tag (ALT) and DIN standard solder pin (ALP)
- Long life, up to 26,000 hours at +85°C (V_R , I_R applied)
- · ALC snap-in should be considered for new designs



ALP	22A		AB	0.	10
Series	Version	Capacitance Code (µF)	Size Code	Rated Voltage (VDC)	
ALP = Solder pin ALT = Solder tag	22A = Standard 23A = Threaded Mounting Stud (ALT only)	First two digits represent significant figures. Third digit specifies number of zeros.	See Dimension Table	040 = 40 063 = 63 100 = 100 200 = 200	250 = 250 385 = 385 400 = 400 450 = 450

4IVJSVQERGI 'LEVEGXIVMWXMGW

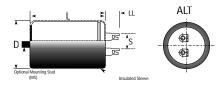
- XIQ		4IVJSVQERGI 'LEVEGXIVMWXMG				
Capacitance Range	22 – 150,000 μF					
Rated Voltage	40 – 450 VDC					
Operating Temperature	-40 to +85°C	-40 to +85°C				
Storage Temperature Rang	e -55 to +85°C					
Capacitance Tolerance	±20% at 100 Hz / +20°C					
	D (mm)	Rated Voltage and Ripple Current at +85°C (hours)				
	25	12,000				
Operational Lifetime	30	15,000				
	35	18,000				
	40	26,000				
End of Life Requiremen	t ± ' ' r					
Shelf Life	2,000 hours at +85°C or 30,000 hours at +40°C 0 VDC					
Lookogo Current	I = 0.006 CV or 6,000 (μA, whichever is smaller)					
Leakage Current	C = rated capacitance (μF), V = rated voltage (VDC). Voltage applied for 5 minutes at +20°C.					
Standards	IEC 60384–4					

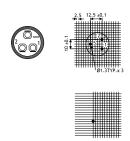
7YVKI :SPXEKI

' S R H M X M		:SPXEKI :('				
3 K H W A W	40	63	100	200	385	
• W WYVKI	G]GP416WE	X 72.5q'	115	230	423.5	



Conditions	Performance			
Temperature	+85°C			
Test Duration	5,000 hours			
Ripple Current	Maximum ripple current specified in table			
Voltage	The sum of DC voltage and the peak AC voltage must not exceed the rated voltage of the capacitor			
Canacitanas Changa	≤ 100 V	Within 15% of the initial value		
Capacitance Change	> 100 V	Within 10% of the initial value		
Equivalent Series Resistance	Does not exceed 200% of the initial value			
Leakage Current	Does not exceed leakage current limit			







The capacitance, ESR and impedance of a capacitor will not change significantly after extended storage periods, however the leakage current will very slowly increase. KEMET products are particularly stable and allow a shelf life in excess of three years at 40°C. See sectional specification under each product series for specific data.

Apply the rated voltage to the capacitor at room temperature for a period of one hour, or until the leakage current has fallen to a steady value below the specified limit. During re-aging a maximum charging current of twice the specified leakage current or 5 mA (whichever is greater) is suggested.

The reliability of a component can be defined as the probability that it will perform satisfactorily under a given set of conditions for a given length of time.

In practice, it is impossible to predict with absolute certainty how any individual component will perform; thus, we must utilize probability theory. It is also necessary to clearly define the level of stress involved (e.g. operating voltage, ripple current, temperature and time). Finally, the meaning of satisfactory performance must be defined by specifying a set of conditions which determine the end of life of the component.

Reliability as a function of time, R(t), is normally expressed as: R(t)=e- $^{\lambda t}$ where R(t) is the probability that the component will perform satisfactorily for time t, and λ is the failure rate.

The failure rate is the number of components failing per unit time. The failure rate of most electronic components follows the characteristic pattern:

- Early failures are removed during the manufacturing process.
- The operational life is characterized by a constant failure rate.
- The wear out period is characterized by a rapidly increasing failure rate.

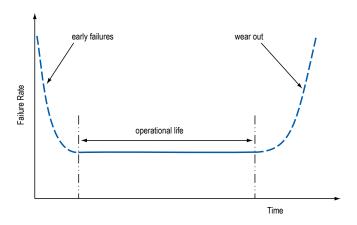
The failures in time (FIT) are given with a 60% confidence level for the various type codes. By convention, FIT is expressed as 1 x 10^{-9} failures per hour. Failure rate is also expressed as a percentage of failures per 1,000 hours. e.g., $100 \text{ FIT} = 1 \times 10^{-7}$ failures per hour = 0.01%/1,000 hours

Catastrophic Failure: short circuit, open circuit or safety vent operation Parametric Failure:

- Change in capacitance > ±10%
- · Leakage current > specified limit
- ESR > 2 x initial ESR value



The mean time between failures (MTBF) is simply the inverse of the failure rate. MTBF= $1/\lambda$



As an environmentally conscious company, KEMET is working continuously with improvements concerning the environmental effects of both our capacitors and their production. In Europe (RoHS Directive) and in some other geographical areas like China, legislation has been put in place to prevent the use of some hazardous materials, such as lead (Pb), in electronic equipment. All products in this catalog are produced to help our customers' obligations to guarantee their products and fulfill these legislative requirements. The only material of concern in our products has been lead (Pb), which has been removed from all designs to fulfill the requirement of containing less than 0.1% of lead in any homogeneous material. KEMET will closely follow any changes in legislation world wide and makes any necessary changes in its products, whenever needed.

Some customer segments such as medical, military and automotive electronics may still require the use of lead in electrode coatings. To clarify the situation and distinguish products from each other, a special symbol is used on the packaging labels for RoHS compatible capacitors.

Because of customer requirements, there may appear additional markings such as LF = Lead Free or LFW = Lead Free Wires on the label.





40	4700	20%	AB	25 x 45	ALT22A472AB040
40	10000	20%	СВ	35 x 45	ALT22A103CB040
40	15000	20%	CD	35 x 55	ALT22A153CD040
40	22000	20%	DD	40 x 55	ALT22A223DD040
63	4700	20%	BB	30 x 45	ALT22A472BB063
63	10000	20%	CD	35 x 55	ALT22A103CD063
63	15000	20%	DE	40 x 75	ALT22A153DE063
100	1000	20%	AB	25 x 45	ALT22A102AB100
100	4700	20%	DD	40 x 55	ALT22A472DD100
100	10000	20%	DF	40 x 105	ALT22A103DF100
200	220	20%	AB	25 x 45	ALT22A221AB200
200	680	20%	DB	40 x 45	ALT22A681DB200
200	1000	20%	DD	40 x 55	ALT22A102DD200
200	2200	20%	DF	40 x 105	ALT22A222DF200
385	100	20%	AB	25 x 45	ALT22A101AB385
385	150	20%	BB	30 x 45	ALT22A151BB385
385	470	20%	DD	40 x 55	ALT22A471DD385
385	1000	20%	DF	40 x 105	ALT22A102DF385

- KEMET Logo
- Rated capacitance
- Capacitance tolerance
- Rated voltage
- Climatic Category
- Date of manufacture & Batch No.
- Article code



The manufacturing process begins with the anode foil being electrochemically etched to increase the surface area and then "formed" to produce the aluminum oxide layer. Both the anode and cathode foils are then interleaved with absorbent paper and wound into a cylinder. During the winding process, aluminum tabs are attached to each foil to provide the electrical contact.

The deck, complete with terminals, is attached to the tabs and then folded down to rest on top of the winding. The complete winding is impregnated with electrolyte before being housed in a suitable container, usually an aluminum can, and sealed. Throughout the process, all materials inside the housing must be maintained at the highest purity and be compatible with the electrolyte.

Each capacitor is aged and tested before being sleeved and packed. The purpose of aging is to repair any damage in the oxide layer and thus reduce the leakage current to a very low level. Aging is normally carried out at the rated temperature of the capacitor and is accomplished by applying voltage to the device while carefully controlling the supply current. The process may take several hours to complete.

Damage to the oxide layer can occur due to variety of reasons:

- Slitting of the anode foil after forming
- Attaching the tabs to the anode foil
- Minor mechanical damage caused during winding

A sample from each batch is taken by the quality department after completion of the production process.

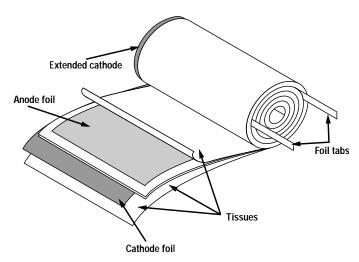
The following tests are applied and may be varied at the request of the customer. In this case the batch, or special procedure, will determine the course of action.

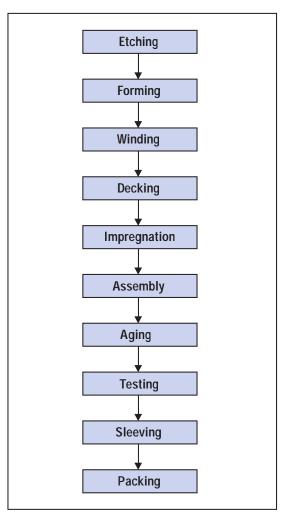
Electrical:

- Leakage current
- Capacitance
- FSR
- Impedance
- Tan Delta

Mechanical/Visual:

- Overall dimensions
- · Torque test of mounting stud
- Print detail
- Box labels
- Packaging, including packed quantity







For a complete list of our globa	sales offices, please visit www.l	remet.com/sales.
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All product specifications, statements, information and data (collectively, the "Information") in this datasheet are subject to change. The customer is responsible for checking and verifying the extent to which the Information contained in this publication is applicable to an order at the time the order is placed.